Form PTO-1595 (Rev. 08/05) OMB No. 0651-0027 (exp. 6/30/2008)	U.S. DEPARTMENT OF COMMERCE United States Patent and Trademark Office		
	SONLY 86737-99		
To the Director of the U.S. Patent and Trademark Office: Please record the attached documents or the new address(es) below.			
1. Name of conveying party(ies)	2. Name and address of receiving party(ies)		
Interconnect Devices, Inc.	Name: Madison Capital Funding, LLC,		
	Internal Address: as agent		
Additional name(s) of conveying party(ies) attached? Yes X No  3. Nature of conveyance/Execution Date(s):  Execution Date(s) April 3, 2009  Assignment Merger	Street Address: 30 S. Wacker		
Security Agreement Change of Name	City: Chicago		
Joint Research Agreement	State:IL		
Government Interest Assignment  Executive Order 9424, Confirmatory License  First Amendment to Patent  Confirmatory License  Africa Amendment to Patent  Africa Security Agreement	Country: USA Zip: 60606		
	Additional name(s) & address(es) attached? Yes X No document is being filed together with a new application.		
A. Patent Application No.(s)	B. Patent No.(s)		
Additional numbers at  5. Name and address to whom correspondence concerning document should be mailed:	tached? XYes No  6. Total number of applications and patents involved: 37		
Name: Laura Konrath			
Internal Address: Winston & Strawn LLP	7. Total fee (37 CFR 1.21(h) & 3.41) \$\) 1,480 Authorized to be charged by credit card		
	X Authorized to be charged by credit card		
Street Address: 35 W. Wacker Dr.	Enclosed		
31/31/7/01/050	None required (government interest not affecting title)		
City: Chicago	8. Payment Information		
77	a. Credit Card Last 4 Numbers		
State. Zip.	Expiration Date		
Phone Number: 312-558-6352 Fax Number: 312-558-5700	b. Deposit Account Number <u>232428</u>		
Email Address: / 1konrath@winston.com	Authorized User Name <u>Laura Konrath</u>		
9. Signature: Signature	1 1 20/09 Date 09		
Lauxa Konrath  Name of Person Signing	Total number of pages including cover sheet, attachments, and documents:		
ranio di i diponi digining	<u> </u>		

Documents to be recorded (including cover sheet) should be faxed to (571) 273-0140, or mailed to: Mail Stop Assignment Recordation Services, Director of the USPTO, P.O.Box 1450, Alexandria, V.A. 22313-1450

Continuation I ten 4

## EXHIBIT A

## PATENT REGISTRATIONS AND PATENT APPLICATIONS

Title Short Title	Country App. No. Grant No.	Status App. Date Grant Date
APPARATUS FOR TESTING A NUNPACKAGED DIE	United States 08/060,614 5,656,945	Granted 5/12/1993 8/12/1997
SHEET METAL INTERCONNECT ARRAY	United States 29/194,881 D525,207	Granted 12/2/2003 7/18/2006
MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	United States 10/700,401 6,890,185	Granted 11/03/2003 5/10/2005
MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	United States 11/125,035 7,217,138	Granted 5/9/2005 5/15/2007
MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	WO PCT/US2004/028;	Gone National 00 8/31/2004
MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	Korea 2006-7010770	Pending 8/31/2004
SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	United States 10/759,338 7,059,865	Granted 1/16/2004 6/13/2006
SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	Malaysia P[20043349	Pending 8/18/2004

SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	WO PCTU\$2004/ 028126	Gone National 8/18/2004
SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	United States 11/077,054 7,189,078	Granted 3/10/2005 3/13/2007
***************************************		
TEST SOCKET FOR AN IC DEVICE	United States 08/538,956 6,046,597	Granted 10/4/1995 4/4/2000
	*************************	***************************************
TEST SOCKET FOR AN IC DEVICE	United States 09/542,131 6,559,665	Granted 4/4/2000 5/6/2003
COVER ASSEMBLY FOR AN IC SOCKET	United States 09/272,629 6,354,859	Granted 3/18/1999 3/12/2002
IC CHIP SOCKET AND	United States	C1
METHOD	09/032,361 6,220,870	Granted 2/27/1998 4/24/2001
PROBE TIP AND METHOD FOR MAKING ELECTRICAL CONTACT WITH A SOLDER BALL CONTACT OF AN INTEGRATED CIRCUIT DEVICE	United States 09/014,100 6,208,155	Granted 1/27/3998 3/27/2001
CONNECTOR, CONNECTOR	United States	Granted
SYSTEM AND METHOD OF MAKING A CONNECTOR	09/049,802 6,042,387	3/27/1998 3,28,2000
TEST SOCKET AND METHOD FOR TESTING AN IC DEVICE IN A DEAD BUG ORIENTATION	United States 09/602,924 6,297,654	Granted 6/22/200 10/2/2001
BUTTON CONTACT FOR SURFACE MOUNTING AN IC DEVICE TO A CIRCUIT	United States 08/531,367 5,629,837	Granted 9/20/1995 5/13/1997
BOARD		
MODULAR SEMICONDUCTOR PACKAGE TESTING CONTACTOR SYSTEM	Taiwan 94123694	Pending 7/13/2005
MODULAR CONTACTOR SYSTEM, SPRING PROBE BASED	United States 60/587,761	Completed 7/14/2004

W	in	$\operatorname{stc}$	n	8z	Str	awn
77	<b>T</b> 11	$o \cdot v$	'11	OL.	$\sim$ $\sim$ $\sim$	awii

MODULAR SEMICONDUCTOR PACKAGE TESTING CONTACTOR SYSTEM	United States 11/177,673 7,189,092	Granted 7/8/2005 3/13/2007
ACTIVE TEST SOCKET	United States 11/671,963	Pending 2/6/2007
ACTIVE TEST SOCKET	Untied States 60/765,555	Completed 2/6/2006
INTERCONNECT ASSEMBLY FOR A PROBE CARD	United States 11/198,995 7,217,139	Granted 8/8/2005 5/15/2007
INTERCONNECT ASSEMBLY FOR A PROBE CARD	WO PCT/US2005/02824	Gone National 40 8/9/2005
COMPRESSIVE CONDUCTORS FOR SEMICONDUCTOR TESTING	United States 11/671,942	Pending 2/6/2007
COMPRESSIVE CONDUCTORS FOR SEMICONDUCTOR TESTING	United States 60/765,710	Completed 2/6/2006
CRIMPED TUBE ELECTRICAL TEST SOCKET PIN	United States 11/671,986 7,297,004	Granted 2/6/2007 11/20/2007
CRIMPED TUBE ELECTRICAL TEST SOCKET PIN	United States 60/765,549	Completed 2/6/2006
MICRO- COAX/COMPRESSIBLE CONDUCTOR CONTACTOR	United States 11/675/521	Pending 2/15/2007
MICRO- COAX/COMPRESSIBLE CONDUCTOR CONTACTOR	United States 60/775,301	Completed 2/21/2006
INTERCONNECT ASSEMBLY FOR TESTING INTEGRATED CIRCUIT PACKAGES	United States 60/735,937	Completed 11/10/2005
INTERCONNECT ASSEMBLY FOR TESTING INTEGRATED CIRCUIT PACKAGES	United States 60/735,939	Completed 11/10/2005
BUNDLE PROBE United States APPARATUS FOR MULTIPLE TERMINAL CONTACT	Granted 09/775,676 7,064,564	2/1/2001 6/20/2006
SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID	China 200480042418.3	Pending 8/30/2004



#### PATENT LICENSES

Irrevocable and perpetual, non-exclusive, royalty-free, fully-paid up, and worldwide
license to make, use, sell, import, export, copy, prepare derivative works based on,
distribute in any manner or medium, and otherwise commercially exploit the following
intellectual property in connection with the package test division which engages in the
design, manufacturing, marketing and sale of machined spring probe based test sockets
and related components which are used by semiconductor companies in validation testing
of integrated circuits (the "Business"):

**Execution Copy** 

# FIRST AMENDMENT TO PATENT SECURITY AGREEMENT

This FIRST AMENDMENT TO PATENT SECURITY AGREEMENT (this "Amendment"), dated as of April 3, 2009, is between INTERCONNECT DEVICES, INC., a Delaware corporation (the "Grantor") and MADISON CAPITAL FUNDING LLC, as "Agent" for the Lenders.

#### WITNESSETH:

WHEREAS, the Grantor and the Agent are party to that certain Patent Security Agreement dated as of May 11, 2007 (as amended, restated, supplemented or otherwise modified from time to time, the "Patent Security Agreement");

WHEREAS, since the filing of the Patent Security Agreement, the Grantor has acquired additional Patents;

WHEREAS, the Grantor wishes to amend the Patent Security Agreement as set forth herein, and the Agent is agreeable to the same, subject to the terms and conditions hereof;

- NOW, THEREFORE, in consideration of the premises and of the mutual covenants contained herein, and other good and valuable consideration the receipt and adequacy of which are hereby acknowledged, the parties hereto hereby agree as follows:
- 1. <u>Amendment</u>. <u>Schedule 1</u> of the Patent Security Agreement is amended by adding thereto the Patent Applications, the Patent Registrations and the Patent Licenses listed on <u>Exhibit</u> A attached hereto.
  - 2. <u>Miscellaneous</u>. The parties hereto hereby further agree as follows:
- (a) <u>Counterparts</u>. This Amendment may be executed in one or more counterparts, each of which, when executed and delivered, shall be deemed to be an original and all of which counterparts, taken together, shall constitute but one and the same document with the same force and effect as if the signatures of all of the parties were on a single counterpart, and it shall not be necessary in making proof of this Amendment to produce more than one (1) such counterpart.
- (b) <u>Governing Law.</u> THIS AMENDMENT SHALL BE GOVERNED BY, AND CONSTRUED AND ENFORCED IN ACCORDANCE WITH, THE INTERNAL LAWS AND DECISIONS OF THE STATE OF ILLINOIS (WITHOUT REFERENCE TO CONFLICT OF LAWS PRINCIPLES).
- (c) <u>No Other Amendments</u>. Except as expressly amended hereby, the Patent Security Agreement shall remain unaltered and in full force and effect.

[signature page follows]

CHI:2239468.2

IN WITNESS WHEREOF, the undersigned have executed this Amendment as of the day and year first above written.

INTERCONNECT DEVICES, INC.

Name: Mark W. Deuel

Title: Chief Financial Officer, Treasurer and

Secretary

MADISON CAPITAL FUNDING LLC, as Agent

Signature Page to First Amendment to Potent Security Agreement

IN WITNESS WHEREOF, the undersigned have executed this Amendment as of the day and year first above written.

# INTERCONNECT DEVICES, INC.

Ву:	-	
Name:		
Title:		
MADISON CAPI	TAL BUNDING IT C	

MADISON CAPITAL FUNDING LLC, as Agent

Name: SUNIL MEHTA

Title: VILE PRESIDENT

Signature Page to First Amendment to Patent Security Agreement

# EXHIBIT A

# PATENT REGISTRATIONS AND PATENT APPLICATIONS

Title Short Title	Country App. No. Grant No.	Status App. Date Grant Date
APPARATUS FOR TESTING A NONPACKAGED DIE	United States 08/060,614 5,656,945	Granted 5/12/1993 8/12/1997
SHEET METAL INTERCONNECT ARRAY	United States 29/194,881 D525,207	Granted 12/2/2003 7/18/2006
MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	United States 10/700,401 6,890,185	Granted 11/03/2003 5/10/2005
MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	United States 11/125,035 7,217,138	Granted 5/9/2005 5/15/2007
MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	WO PCT/US2004/02R2	Gone National no 8/31/20 <b>04</b>
 MULTIPATH INTERCONNECT WITH MEANDERING CONTACT CANTILEVERS	Korea 2006-7010770	Pending 8/31/2004
SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	United States 10/759,338 7,059,865	Granted 1/16/2004 6/13/2006
 SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	Malaysia PI20043349	Pending 8/18/2004
	***************************************	

SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	WO PCTUS2004/ 028126	Gone National 8/18/2004
••••	***************************************	**
SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID PROVIDING SPRING SUSPENSION	United States 11/077,054 7,189,078	Granted 3/10/2005 3/13/2007
TEST SOCKET FOR AN IC DEVICE	United States 08/538,956 6,046,597	Granted 10/4/1995 4/4/2000
****		
TEST SOCKET FOR AN IC DEVICE	United States 09/542,131 6,559,665	Granted 4/4/2000 5/6/2003
COVER ASSEMBLY FOR AN IC SOCKET	United States 09/272,629 6,354,859	Granted 3/18/1999 3/12/2002
	, ,	
IC CHIP SOCKET AND METHOD	United States 09/032,361 6,220,870	Granted 2/27/1998 4/24/2001
PROBE TIP AND METHOD FOR MAKING ELECTRICAL CONTACT WITH A SOLDER BALL CONTACT OF AN INTEGRATED CIRCUIT DEVICE	United States 09/014,100 6,208,155	Granted 1/27/1998 3/27/2001
CONNECTOR, CONNECTOR	United States	Granted
SYSTEM AND METHOD OF MAKING A CONNECTOR	09/049,802 6,042,387	3/27/1998 3,28,2000
TEST SOCKET AND METHOD FOR TESTING AN IC DEVICE IN A DEAD BUG ORIENTATION	United States 09/602,924 6,297,654	Granted 6/22/200 10/2/2001
BUTTON CONTACT FOR	71 's 10.	
SURFACE MOUNTING AN IC DEVICE TO A CIRCUIT BOARD	United States 08/531,367 5,629,837	Granted 9/20/1995 5/13/1997
MODULAR SEMICONDUCTOR PACKAGE TESTING CONTACTOR SYSTEM	Taiwan 94123694	Pending 7/13/2005
MODULAR CONTACTOR SYSTEM, SPRING PROBE BASED	Uniled States 60/587,761	Completed 7/14/2004

Winston	ւ & լ	Strawn	

MODULAR SEMICONDUCTOR PACKAGE TESTING CONTACTOR SYSTEM	United States 11/177,673 7,189,092	Granted 7/8/2005 3/13/2007
ACTIVE TEST SOCKET	United States 11/671,963	Pending 2/6/2007
ACTIVE TEST SOCKET	United States 60/765,555	Completed 2/6/2006
INTERCONNECT ASSEMBLY FOR A PROBE CARD	United States 11/198,995 7,217,139	Granted 8/8/2005 5/15/2007
INTERCONNECT ASSEMBLY FOR A PROBE CARD	WO PCT/US2005/028240	Gone National 8/9/2005
COMPRESSIVE CONDUCTORS FOR SEMICONDUCTOR TESTING	United States 11/671,942	Pending 2/6/2007
COMPRESSIVE CONDUCTORS FOR SEMICONDUCTOR TESTING	United States 60/765,710	Completed 2/6/2006
CRIMPED TUBE ELECTRICAL TEST SOCKET PIN	United States 11/671,986 7,297,004	Granted 2/6/2007 11/20/2007
CRIMPED TUBE ELECTRICAL TEST SOCKET PIN	United States 60/765,549	Completed 2/6/2006
MICRO- COAX/COMPRESSIBLE CONDUCTOR CONTACTOR	United States 11/675/521	Pending 2/15/2007
MICRO- COAX/COMPRESSIBLE CONDUCTOR CONTACTOR	United States 60/775,301	Completed 2/21/2006
INTERCONNECT ASSEMBLY FOR TESTING INTEGRATED CIRCUIT PACKAGES	United States 60/735,937	Completed 11/10/2005
INTERCONNECT ASSEMBLY FOR TESTING INTEGRATED CIRCUIT PACKAGES		Completed 11/10/2005
BUNDLE PROBE United States APPARATUS FOR MULTIPLE TERMINAL CONTACT		2/1/2001 6/20/2006
SEE-SAW INTERCONNECT ASSEMBLY WITH DIELECTRIC CARRIER GRID		Pending 8/30/2004

PROVIDING SPRING SUSPENSION		
INTERCONNECT ASSEMBLY FOR TESTING INTEGRATED CIRCUIT PACKAGES	United States 11/558,591	Pending 11/10/2006
INTERCONNECT ASSEMBLY FOR TESTING INTEGRATED CIRCUIT PACKAGES	United States 11/558,603 7,402,051	Granted 11/10/2006 7/22/2008
INTERCONNECT ASSEMBLY FOR A PROBE CARD	China 200580026854.6	
INTERCONNECT ASSEMBLY FOR A PROBE CARD	Korea 2007-7004850	Pending 8/9/2005
INTERCONNECT ASSEMBLY FOR A PROBE CARD	Philippines 2007-500354	Pending 8/9/2005
TEST INTERCONNECT	United States 12/054,281	Pending 3/24/2008
IMPEDANCE-MATCHED TEST SOCKET AND METHOD OF MANUFACTURING SAME	United States 61/022,675	Pending 1/22/2008
IMPEDANCE-MATCHED TEST SOCKET OF MANUFACTURING SAME	United States 61/038/614	Pending 3/21/2008
SPRING PROBE	United States 12/105,922	Pending 4/18/2008

#### PATENT LICENSES

Irrevocable and perpetual, non-exclusive, royalty-free, fully-paid up, and worldwide
license to make, use, sell, import, export, copy, prepare derivative works based on,
distribute in any manner or medium, and otherwise commercially exploit the following
intellectual property in connection with the package test division which engages in the
design, manufacturing, marketing and sale of machined spring probe based test sockets
and related components which are used by semiconductor companies in validation testing
of integrated circuits (the "Business"):

4/21/2009 2:41:01 PM PAGE 015/015

 us Patent Application – "Thermally Balanced Heatsinks" (Docket No. 9606-283) (inventors – Chris Lopez and Trevor Moody)

37

Fax Server

PATENT REEL: 022629 FRAME: 0041

Winston & Strawn